Electronic Supporting Information

Ion Diffusivities in Nanoconfined Interfacial Water Films Contribute to Mineral Carbonation Thresholds

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			H ₂ O		in situ X	RD phase abu	ndance (wt %) ^c		Corrected in			
Experiment ID ^a T/RH	Temperature (°C)	RH (%)	solubility in 90 atm scCO ₂ (mol %) ^b	Reaction time (hrs.)	Forsterite Mg ₂ SiO ₄	Magnesite MgCO ₃	Nesquehonite MgCO ₃ ·3H ₂ O	TGA-MS carbonate abundance (wt %). ^c	situ XRD carbonate abundance ^d (wt %) ^c	k (s ⁻¹), carbonation rate constant	Uncertainty in k (%) ^e	R ² of kinetic model fit
EXP 1 65/100	65	100	0.608	45.0	13	87	ndf	68	67	1.61E-05	10	0.93
EXP 2 65/85	65	85	0.517	44.7	64	36	ndf	34	32	2.37E-06	10	>0.99
EXP 3 50/100	50	100	0.378	121.5	ndf	99	1	65	73	n/a ^g	n/a ^g	n/a ^g
EXP 4 50/85	50	85	0.321	121.4	100. ^h	nd ^{f, h}	ndf	23	NC ^{<i>i</i>}	5.15E-07 ^j	24	0.90 ^j
EXP 5 50/85	50	85	0.321	121.5	100. ^h	nd ^{f, h}	nd ^f	23	NC ^{<i>i</i>}	5.15E-07 ^{<i>j</i>}	24	0.90 ^j
EXP 6 50/85	50	85	0.321	45.6	100 ^h	nd ^{f, h}	nd ^f	17	NC ⁱ	5.15E-07 ^j	24	0.90/
EXP 7 35/100	35	100	0.367	262.4	2	nd ^f	98	81	81	4.92E-06	10	0.92
EXP 8 35/85	35	85	0.312	171.1	86	ndf	14	23	13	1.35E-07	10	0.94

Table S1. Experimental parameters and results for EXP 1-8

Abbreviations: scCO₂ – supercritical CO₂; XRD - high pressure X-ray diffraction; TGA-MS - thermogravimetric mass spectrometry, RH-relative humidity (% H₂O saturation of scCO₂) ^a Experiments were conducted at 90 atm with 10 µl of H₂O or 4.0 *m* NaCl solution in the reactor fluid reservoir. The *in situ* XRD reactor contained 0.55, 0.75, and 1.55 g of CO₂ at 65, 50, and 35 °C, respectively. Carbon dioxide density at 90 (c.f. Miller et al.¹), 65, 50, and 35 °C and 90 atm is 178.51, 225.21, 294.77, and 670.24 kg/m^{3.2}

^b calculated using solubility model of Springer et al.³

 $^{\rm c}\pm 5$ wt % uncertainty

^d Corrected *in situ* XRD abundance accounts for the presence of amorphous silica

^eAt least 10X the uncertainty calculated in SigmaPlot 12.5¹

f not detected

g not applicable, due to simultaneous nesquehonite and magnesite growth, the interpolated value is 9.19x10⁻⁶ s⁻¹.

^h in situ and ex situ evidence of magnesite detected, but in situ XRD quantification not possible, see text

ⁱ not calculated, due to lack of *in situ* XRD quantifiable magnesite

^j k, k uncertainty, and R² for 50/85 condition determined using *ex situ* TGA-MS results from EXP 4-6 (see text)

%RH at 50 °C and 90 bar scCO ₂	Water film thickness (ML)	Water film thickness (nm)		
100	5.0	0.92		
85	3.6	0.64		
70	2.4	0.42		

Table S2. Water film thicknesses on forsterite exposed to wet supercritical CO_2 as a function of relative humidity (RH). Water film thickness in monolayers (ML) determined by interpolated/extrapolated measurements from Miller et al.⁴, and the water density profile at the (010) forsterite surface derived from the MD simulations of Kerisit et al.^{5, 6} were used to determined water film thicknesses in nanometers (nm).

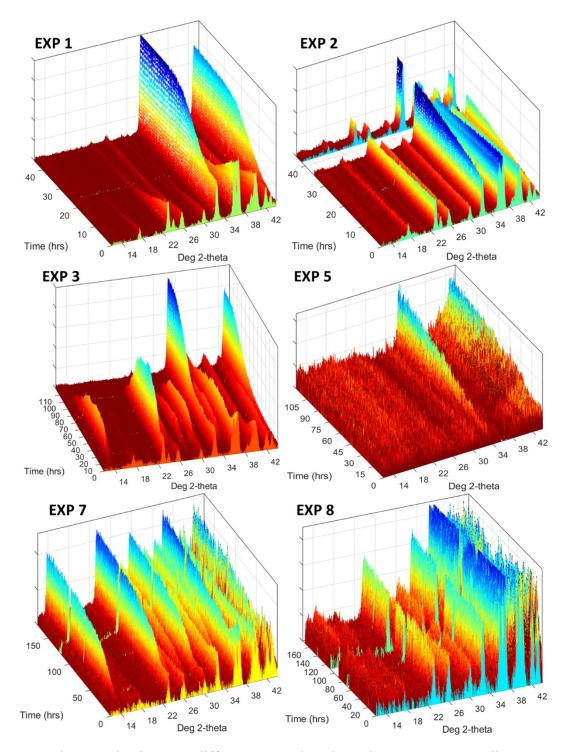


Figure S1. Time-resolved *in situ* diffractograms that show the appearance or disappearance of peaks corresponding to magnesite and/or nesquehonite precipitation and forsterite dissolution at 35-65 °C and 90 atm at 100% and 85% RH. Relative intensity scales are unique to each figure, and cooler colors indicate higher intensities. The EXP 5 plot shows the differential XRD (DXRD) results, in which the initial (t=200 s) *in situ* scan was subtracted from each following pattern to best visualize the growth of magnesite peaks, with only positive intensities shown.

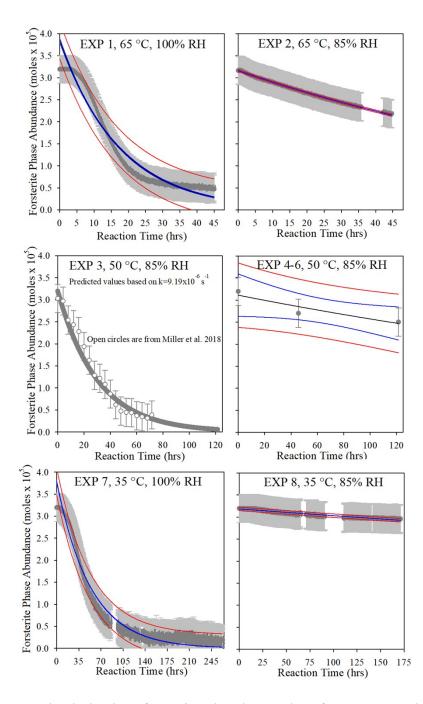


Figure S2. Time-resolved absolute forsterite abundance plots for EXP 1-8 showing Mg_2SiO_4 dissolution at 35-65 °C and 90 atm scCO₂ at 100% or 85% RH. Forsterite abundances are denoted by dark grey circles with light grey error bars, and the kinetic model fits (black curve) are shown along with the 95% confidence (blue) and prediction (red) envelopes. The middle left panel (EXP 3) shows a predicted dataset (dark grey curve) of time-resolved forsterite abundances for a rate constant (k) of 9.19x10⁻⁶ s⁻¹. The rate constant was predicted based on interpolation of the **Fig. 4** Arrhenius plot. For comparison (see text for discussion), data from Miller et al.⁷ (open circles) is shown.

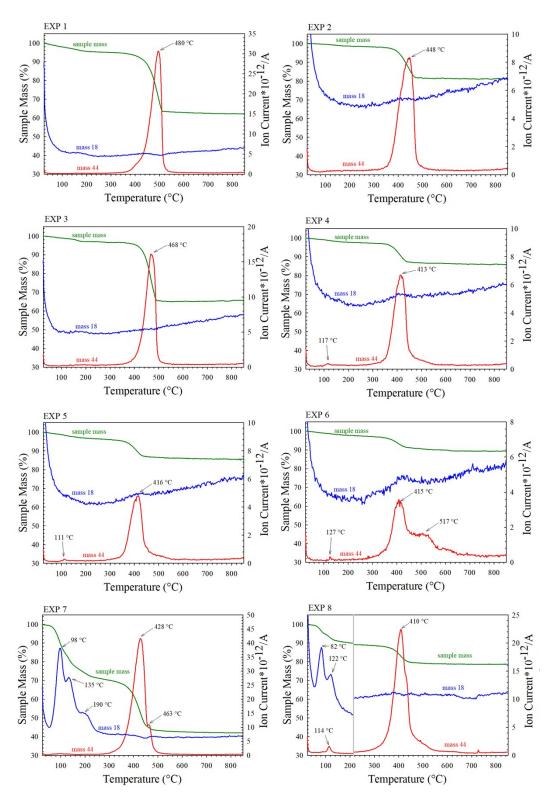


Figure S3. TGA-MS results for EXP 2-8. EXP 1 TGA-MS results reported in Miller et al.¹. EXP 8 is a composite of two TGA-MS measurements on the same sample, as the first heating ramp was interrupted at ~210 °C.

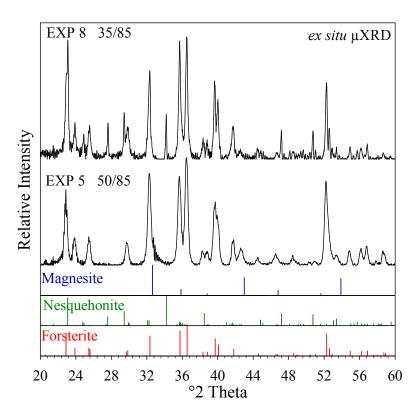


Figure S4. *Ex situ* XRD patterns of EXP 5 and EXP 8. Reference lines in this figure and others correspond to the International Centre for Diffraction Data powder diffraction files (PDF) for forsterite (#34-0189), nesquehonite (#20-0669), and magnesite (#8-0479).

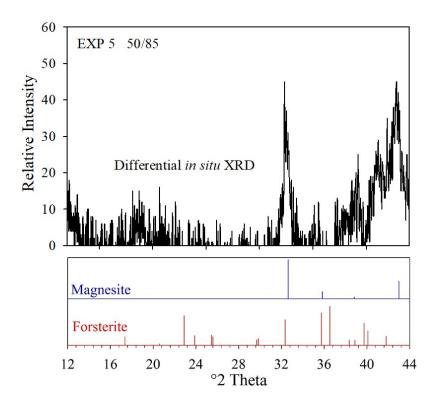


Figure S5. The presence of magnesite peaks is evident in the differential XRD (DXRD) pattern produced by the first and last *in situ* EXP 5 (50/85) diffractograms, with only positive intensities shown.

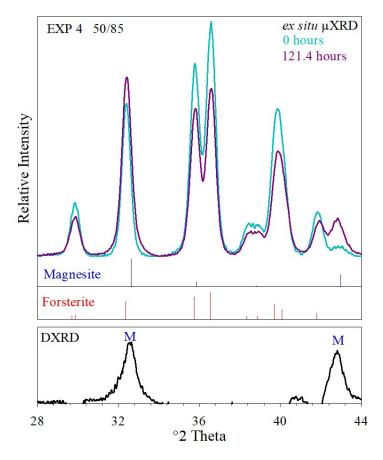


Figure S6. Magnesite (M) peaks are evident in the DXRD pattern produced by the first (cyan) and last (purple) *ex situ* EXP 4 (50/85) diffractograms.

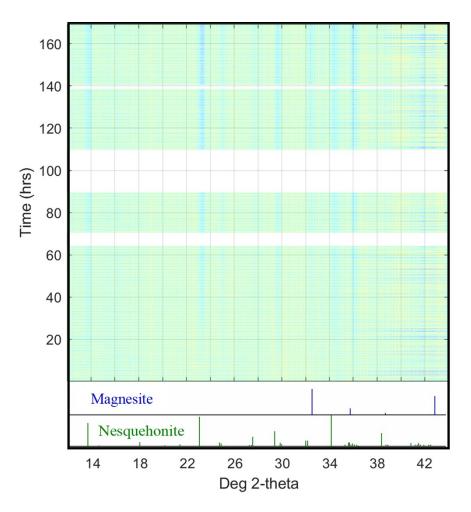


Figure S7. Time-resolved differential XRD results for **EXP 8** (35/85), in which the initial *in situ* scan was subtracted from each following pattern to best visualize the growth of peaks corresponding to nesquehonite. The relative intensities are depicted with an inverse heat scale and the powder diffraction reference files are plotted for clarity.

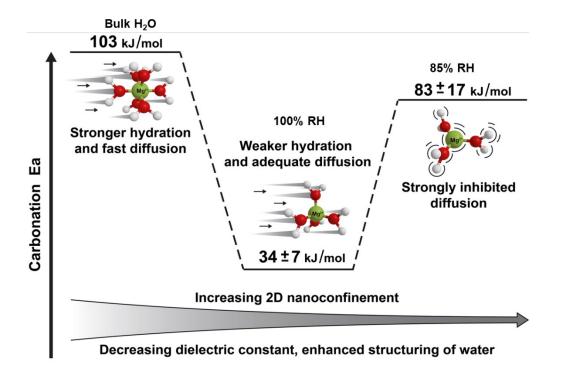


Figure S8. Conceptual illustration of forsterite carbonation "sweet spot" in an interfacial water film due to competing effects between ion hydration and diffusion. See main text (Section 3.3) for discussion.

References

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